

# Sensor Principles

Integrated Interface Circuits •Errors and Noise  
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Integrated Interface Circuits •Introduction  
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? Lectures: •Mondays: 11:30 AM until 1 PM ?  
Seminar at the end of the lecture  
period/beginning of the lecture free period ?  
Participation in the seminar is mandatory for  
taking the exam ? The exam will be a written  
exam

? Introduction/Motivation •Why/where do we  
need sensors? •What are the  
challenges/problems in reading out the  
sensors? ? Noise and other sources of error ?  
Categorizing different types of sensor

•Self-generating vs. modulating sensors  
•Electrical behavior ? Readout Concepts  
•Absolute vs. differential measurements •AM  
vs. FM detection •Resonant readouts •Phase  
sensitive-detection (Lock-in amplifiers)

•Continuous-time vs. discrete time readout  
? Readout Concepts (cont.) •Open-loop vs.  
Closed loop measurements ? Readout Circuit  
Implementations •Instrumentation amplifiers  
•Transimpedance amplifiers

•Switched-capacitor readout circuits ?  
Data-converters for sensor readouts •A/D  
converters •D/A converters •T/D converters (if  
time permits)

? Medical applications (1/2): MRI, Ultrasound  
www.medical.siemens.com

http://www.magnet.fsu.edu/

www.sciencephoto.com

http://www.healthcare.philips.com

http://www.nibib.nih.gov/

http://www.gehealthcare.com/

? Medical applications (2/2): CT, PET/CT

http://www.toshiba-medical.eu/

http://www.healthcare.philips.com

http://www.cyberphysics.co.uk/

http://neuros.net/

http://www.uib.no http://www.siemens.com/

? Automotive applications

http://www.toyota.co.uk/

http://auto.howstuffworks.com

http://newsimages.motoring.co.uk/

http://www.eetimes.com/

http://i.telegraph.co.uk/

? Consumer electronics

http://www.arj.no/2007/01/14/iphone-sensing/

http://www.kinectingforwindows.com/

http://pertemi.wordpress.com/

http://www.touchuserinterface.com/

? Applications in Science/Metrology

http://www.brucker.com

http://simple.wikipedia.org

Source: Prof. Keller, Uni Graz

Array of Photodiodes Pixel A/D converter

? Sensors sense their environment ? Sensors  
can produce electrical or non-electrical signals  
transduction might be required ? Interface  
electronics typically, amplify, frequency  
convert, filter and A/D convert the sensed  
signal

REVIEW OPAMP BASICS

? Maximum input voltage in open loop

configuration:

A ? 105, VDD ? ?VSS ? 10 V,V

? 18 V ==  $\frac{1}{2}$  V ? V

/ A ? 90 ? V

0 out, range in, max out, range 0 ? Opamps  
should be used in closed loop configuration ?  
Tradeoff between open loop gain and accuracy  
? When using the opamp in feedback, stability  
becomes a concern! ? Stability criterion:  
Simplified Nyquist criterion (negative  
feedback) loop gain: ?? = ?? ? ????

phase margin: ??

= 1 ? PM = 180+ ?

gain margin: ?

= ?180+? GM = 20 ? log10

? Assuming ??? ? ?

Vx ?

? ?Vout

? ? ? A ?? ? ? ? Vin

?Vx ? ?

? ? A ?? ? ? ? Vin

? ? ?Vout ?

?

? Very basic feedback theory •Ao(?) is the  
forward gain (open loop gain) •? is the  
feedback gain •?•Ao(?) is the loop gain •1 + ??  
? ????: feedback factor •Closed-loop TF:

Ao(?) Vin Vout

? There is a tradeoff between open loop gain  
and DC accuracy. ? Tradeoff of gain vs.  
bandwidth. ? Tradeoff of input and output  
resistance. (depending on the type of  
feedback) Buffer example of DC tradeoff:  
Open loop response Closed loop response (??  
= 1) ? Placing the first non-dominant pole  
before or not to close behind the GBW results  
in peaking in the amplitude response of the  
closed loop system

? In the time-domain, placing the non dominant  
pole below or not sufficiently far beyond the  
GBW manifests itself as ringing in the step  
response ? Note: Depending on the  
application, the frequency and/or time-domain  
behavior is more important

Loop gain ?? ? ???? Closed loop gain ???/(1 +  
?? ? ????) ? The worst case in terms of  
stability occurs for ?? = 1 because (assuming a  
passive feedback network) this choice  
maximizes the loop gain

? Assuming a finite value for ?out and a very  
large open loop gain ?0

? How is this condition ensured in the circuit?  
The opamp in the negative feedback loop  
adjusts ?out appropriately ? The potential at  
the opamp's noninverting input is virtually  
copied to the inverting terminal (virtual short)  
? Due to the virtual short between the inverting  
and noninverting opamp inputs, we have:  
? The fact that typical opamps have large  
differential input impedances further attenuate  
the opamp's input current

? Apply KCL to node X

? Feedback factor:

T ?? ?

? Vx? ? Vx

R1 ? A ?? ?

? Closed loop TF: ? ? •Either apply KCL at node  
X or use the finding of slide 16

? If negative feedback is applied around an  
opamp, the following rules apply:

? Important: The rules only apply if the opamp  
operates linearly (e.g. no clipping or oscillation  
at its output)

? Note: The opamp is used in positive  
feedback here (the output is fed back to the  
noninverting input) ? What do we know? ??? ?  
? ? ???? ? 0 for finite ??? ?

? Assume that initially ??? is positive and not  
too large (i.e. ?? VDD) and that the output is at  
zero volts

? ??? j

?out = ?? ? ???? ? ?out becomes positive as

well the constraint ?in = ?FB enforces that

???? further increases ?out and ??? increase  
together until the opamp rails

? Virtual short (???? = ?out) and KCL at nodes  
X and Y

0 ? Vin

?Vx

? ?V

?V ? ? sC

? ?Vout

?Vx ?

? R out x 1 R 1 2

0 ? Vout

?Vx ? V

? sC

out 2 2

? Calculate the input impedance of the circuit  
above!

Zin

? vin i

in ? Hint: Assume an ideal opamp and a  
voltage drive

? Voltage at node 1: ???1 in ? Ideal opamp  
enforces virtual short: ??X3

= ??X1

= ?in

? Ideal opamp: Current through ?1 also flows  
through ??2:

??X2

= ??x3 ? ?1

= ?in ? ? 1

? Ideal opamp: Current through ??conv

is ?in

: ?in

= (??in??x2) ??conv

? The circuit should not be used with a current  
drive ? Voltage drive negative feedback ?

Current drive positive feedback ? Intuitive  
explanation: For current drive there is unity  
gain feedback to the noninverting input and  
less than unity gain feedback to the inverting  
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? Limit of detection (LOD) definition: The  
minimum level of the input quantity which can  
reproducibly be measured at a specified SNR  
(typically: ???NR = ??? ???B) ? Practical  
signals are specified by their dynamic range  
(DR): DR is the ratio between the maximum and  
minimum signal levels occurring within  
inaccuracy levels

? Two different types of error: •Deterministic  
errors e.g. source loading, offset, gain error

•Random (stochastic) errors e.g. thermal  
noise, 1/f noise ? Errors can be quantified as  
absolute errors and relative errors

Absolute error: ??? =

???

? ??0

Relative error: =

where ??0 is the true value and

???

is the measured quantity/the estimate

? The maximum inaccuracy ???max should be  
specified such that the true value lies within  
the interval [?? ? ???max, ?? ? ???max]

? Assumption: The output quantity ?? is  
affected by the ?? parameters ???==1..??  
according to y ? f ?x1, x2, ..., xN ?

? Then, assuming small deterministic  
fluctuations in the ?????? the total error  
in ?? is given by

?y ?

? i ?1

?f ? ?x ?xi

? Consequently, if we denote by ??????,max  
the (small) maximum inaccuracy of each  
?????, then ??? is bounded by

?ymax

? ? i ?1

?f ?xi

? ?x

i ,max

? The partial derivative ???????? ??????????  
is called sensitivity w.r.t. ??????

? If the quantity to be measured depends on  
the 3 parameters ?in, ?error,1 and ?error,2  
according to

y ? G ? xin

? k1 ? xerror,1 ? k2 ? xerror,2

and the uncertainties in ?in, ?error,1 and  
?error,2 are 0 (??in is the perfectly known  
input signal), ???error,1 and ???error,2, the  
uncertainty in y becomes

?y ?

? ?G ? xin

? k1 ? xerror,1 ? k2 ? xerror,2 ? ? ?x ?x  
error,1 ?

? ?G ? xin

? k1 ? xerror,1 ? k2 ? xerror,2 ? ? ?x ?x  
error,2

error,1 error,2 ? k1 ? ?xerror,1 ? k2 ? ?xerror,2 ?

Typical sources of additive errors are: •Offset  
•Additive noise (cave: here rms values need to  
be considered) ? The uncertainty in the

measurand due to additive errors is best  
specified as an absolute error

? Assume that the output ??(?) depends on  
the input Xin and the error source ?error  
according to Y ?? ? ? H ??, xerror ? ? Xin ?? ? ?  
Then, the relative error in ??(?) becomes:

?Y ?? ?

? 1 ? ? ?H ??, xerror ? ? Xin ?? ??? ? ?x

Y ?? ?

Y ?? ?

?xerror

error

? Xin ?? ? ? ?H ??, xerror ? ? ?x

H ??, x ? ? X ?? ? ?x

error

error in error ? 1 ? ?H ??, xerror ? ? ?x

H ??, x ? ?x

error

error error

which is independent of Xin ? Therefore, the  
effect of multiplicative errors is best described  
as a relative error in the output signal

? Interference: •Interference is caused by an  
undesired coupling of external signals into the  
measurement setup •Example: 50 Hz hum ?

Noise: •Noise is caused by random  
fluctuations originating in the measurement  
setup itself •Example: thermal noise ? Both  
noise and interference can usually be modeled  
as additive error signals they can be modeled  
by additional error sources in the system ?

Cave: noise and interference should not be  
confused with signal distortion, which is  
caused by intrinsic system nonlinearities in  
either the amplitude or the frequency domain

Signal @ 1 kHz

? Total signal: ??

= 0.1 ? cos

+ 2 ? cos

+ ??(?)

? ??

has a variation of ??? = 0.01  
? The signal is barely visible in the time  
domain, but easy to see in the frequency  
domain

? Errors are introduced at multiple points along  
the signal processing chain

<p>           ? Examples of such error sources are offset, distortion, noise, crosstalk, cross sensitivity, gain error -? Question: What is the best way to assess their combined effect on the measured signal?            ? General idea: We can only compare the effect of two different error sources when they are referred to the same point along the signal processing chain ? Two natural choices for the comparison points are the overall input and the overall output (input allows for an intuitive comparison with the measurand)            ? For linear(ized) systems the superposition principle applies: Refer all error sources to the output and then refer them to the input by dividing by the overall signal gain ?            Deterministic sources of error:            ? Random uncorrelated sources of error:            ? Output referred error: The effect of an error source on the overall output is called the output referred error ? Input referred error: The equivalent effect of an error source on the overall input is called the (equivalent) input referred error            ? Example for finding the equivalent input and output referred noise: Error source: ????? Find TF from ????? to the output ?? : ?????,??2 ?            ??out,??2 = ?????,??2 ? ????? Refer the result back to the input using the overall TF ?????,?? : ?????            = ??out,??2 ?????,??            = ?????,??2            ? ?????2 ?????,??            ? Fluctuations of a physical quantity can be mathematically modeled as a random or stochastic process ? A random process (r.p.) can be seen as a family of functions ?? where ??(?? = ??0) is a random variable with 1st-order probability density function (pdf) ?????(??, ??)            ? The instantaneous amplitude of the signal ?? only be predicted with probability ?????(??, ??0) at time ??0 can therefore            ? The mean or expected value ?????(??) is obtained by averaging the amplitude ?? at time ?? over all possible realizations of ??(??) ?  <math>mx(t) = E\{x(t)\}</math>  <math>\int x \cdot px(x,t)dx</math> ??            ? The autocorrelation function (ACF) is a measure of the statistical dependence between the random variables ?? epochs            and ??(??2) at two different  <math>R_x(t_1,t_2) = E[x(t_1)x(t_2)]</math>  <math>?? \cdot ?? \cdot ??</math> ??  <math>x_1 \cdot x_2</math>  <math>\int px(x_1, x_2, t_1, t_2) dx_1 dx_2</math>            where ?????(??1, ??2, ??1, ??2) is the 2nd-order pdf of ??(??) ? The autocovariance is defined by  <math>C_x(t_1,t_2) = E\{x(t_1) \cdot mx(t_1) - x(t_2) \cdot mx(t_2)\}</math> ??  <math>R_x(t_1,t_2) = mx(t_1) \cdot mx(t_2)</math> </p>	<p>           ? A random process is called wide sense stationary (WSS) if its mean is independent of ?? and its ACF only depends on the time difference ?? = ??2 ? ??1  <math>mx(t) = mx</math>            ? const.  <math>R_x(t_1,t_2) = R_x(t_2 - t_1) = R_x(\tau)</math>  <math>C(t, t) = C(t - t) = C</math>  <math>(\tau) = R(\tau) = m^2</math>  <math>x_1^2</math>  <math>x_2^2</math>  <math>x \cdot x</math>            ? The normalized ACF (aka correlation coefficient) is defined as  <math>\rho(\tau) = C_x(\tau) / C</math>, where <math>\tau = t_2 - t_1</math>  <math>(\tau = 0)</math> is the so-called variance  <math>\int x^2 \cdot x \cdot x</math> ? For real random processes one can show that:  <math>R_x(\tau) = R_x(-\tau)</math>, <math>C_x(\tau) = C_x(-\tau)</math> <math>C(0) = \int x^2</math>, <math>R(0) = \int x^2 = m^2</math>, <math>\rho(0) = 1</math> <math>x \cdot x \cdot x \cdot x</math>            ? The Power Spectral Density (PSD) of a WSS r.p. <math>x(t)</math> is the Fourier transform of its ACF  <math>S_x(f) = F\{R_x(\tau)\}</math> ??  <math>\int R_x(\tau) \cdot e^{j2\pi f\tau} d\tau</math>  <math>R(\tau) = F^{-1}\{S(f)\}</math> ??  <math>\int S_x(f) \cdot e^{j2\pi f\tau} df</math>  <math>\int S(f) \cdot e^{j2\pi f\tau} df</math>            ? PSD has units of [V2] if ??(??) is a voltage and [A2]            if ??(??) is a current  <math>Hz \cdot Hz</math> ? The above definition defines the so-called double-sided PSD ? Most instruments display the so-called single-sided PSD which is related to the double-sided PSD according to  <math>S(f) = 2S_x(f)</math> for <math>f &gt; 0</math> ?  <math>\int S_x(f) \cdot df</math> for <math>f &gt; 0</math>            ? The total power associated with the r.p. is given by ?  <math>P_x = \int S_x(f) \cdot df</math> ??  <math>\int R_x(0)</math>            ? Note: By definition the rms value is the square root of ????? ? For a noise voltage PSD ?  <math>2 n_{rms}</math>  <math>\int S(f) \cdot df</math> ? <math>n</math> ?? 0  <math>\int (f) \cdot df</math> n            ? For a noise current PSD  <math>2 n_{rms}</math>  <math>\int S(f) \cdot df</math> n ??  <math>\int S(f) \cdot df</math> n 0  <math>R_x(\tau) = x(t) S_x(f)</math>            Impulse response ?(??)            Transfer function ??(??)  <math>R_x(\tau) = x(t) S_x(f)</math>            ? Assuming that the input ?? WSS with ACF         </p>	<p>           is WSS then the output ??(??) will also be ?  <math>R_y(\tau) = R_x(\tau) \cdot \rho_h(\tau) \cdot ??</math> ??  <math>R_x(\tau) = \int x(t) \cdot x(t+\tau) dt</math>  <math>\int (t) \cdot h(t) \cdot h(t+\tau) dt</math>  <math>\int h(t) \cdot h(t+\tau) dt</math>  <math>\int h(t) \cdot h(t+\tau) dt</math>            ? The PSD <math>S_y(f)</math> is given by the Wiener-Khinchine theorem            Three main sources of noise ? Thermal noise            •Due to thermal excitation of charge carriers            •Appears as white spectral density ? Shot noise            •Due to carriers randomly crossing a barrier            •Dependent on DC bias current and is white ? Flicker noise            •Due to traps in semiconductors            •Has a 1/f spectral density            •Significant in MOS transistors at low frequencies            ? EPT: Every closed physical system at temperature T contains an average energy of <math>kT/2</math> per degree of freedom ? Consider a gas of electrons having a Maxwellian velocity distribution ? <math>m v^2 p(v) = e 2kT</math> where ?? ?? ? d?? represents the probability of finding one electron in the velocity interval [??, ?? + d??] ? The average energy of the electron at equilibrium is given by  <math>m m \cdot kT</math>  <math>W = m</math>  <math>\int v^2 \cdot v^2 \cdot p(v) \cdot dv</math> ?  <math>2 \cdot 0 \cdot 2</math>            ? In 3 dimensions, we have ? <math>2 \cdot 2 \cdot 2 \cdot v \cdot vx \cdot vy</math>  <math>\int v^2 = \int v^2</math>  <math>\int 2 \cdot 2 \cdot 2 \cdot 3</math>  <math>v \cdot v</math>  <math>\int 3 \cdot v \cdot vx</math>  <math>= \int W \cdot m \cdot 2</math>  <math>\int kT</math>  <math>A</math> : cross section <math>n</math> : electron density <math>J</math> : current density  <math>U \cdot R \cdot I</math>  <math>\int R \cdot A \cdot J</math>  <math>\int R \cdot A \cdot n \cdot q \cdot v</math>  <math>v \cdot 1 N</math>  <math>\int i \cdot 1</math>  <math>v_i</math>, with: <math>N</math>  <math>\int n \cdot A \cdot L</math>            ? The voltage ?? is then given by:  <math>U \cdot q \cdot R</math>  <math>\int v</math>  <math>\int u</math>, where: <math>u</math>  <math>\int q \cdot R \cdot v</math>  <math>i \cdot i \cdot i \cdot i</math>            ? If no current flows, then <math>\int i \cdot \int i = 0</math>, <math>\int i \cdot \int i = 0</math> and <math>\int i \cdot \int i = 0</math>. ? The variances on the other hand will be nonzero  <math>v^2 \cdot v^2 \cdot 0</math> and <math>U^2 \cdot U^2 \cdot 0</math>            ? The ACF of U is given by  <math>R(\tau) = \int R</math>  <math>(\tau) \cdot \int q \cdot R \cdot \tau</math>  <math>(\tau)</math>  <math>u \cdot u \cdot L \cdot v_i \cdot \tau \cdot i</math> </p>	<p>           where ??????? (??) is the ACF of ??????.            ??????? ? ?            can be modeled as  <math>R(\tau) = R_i</math>  <math>(0) = e</math>  <math>\tau_0</math>, where ?            is the relaxation time and  <math>R(0) = 2 i</math>            ? If ?????? has a Maxwellian distribution we have:  <math>kT = q \cdot R \cdot \tau_2</math>  <math>\int q \cdot R \cdot \tau_2 \cdot kT</math> ??  <math>R(0) = v \cdot 2</math>            and <math>R(\tau) = \tau \cdot R</math>  <math>(\tau) = \tau \cdot \tau \cdot e \cdot \tau_0</math>  <math>v_i \cdot m</math>  <math>u_i \cdot L \cdot v_i</math>  <math>\int L \cdot \tau \cdot m</math>  <math>\tau \cdot \tau \cdot \tau \cdot \tau</math> The corresponding PSD is given by  <math>\int q \cdot R \cdot \tau_2 \cdot kT = \int q \cdot R \cdot \tau_2 \cdot kT</math>  <math>S_u(f) = n \cdot A \cdot L \cdot \tau \cdot \tau</math> ??  <math>\tau \cdot 0</math>  <math>\int n \cdot A \cdot L \cdot \tau \cdot \tau \cdot \tau \cdot \tau \cdot 2 \tau_0</math>            where <math>f \cdot</math>  <math>N \cdot L</math>  <math>m \cdot \tau \cdot \tau \cdot \tau \cdot f \cdot \tau_0</math> ?  <math>\int L \cdot \tau \cdot m</math>  <math>2 \cdot \tau_0</math>  <math>\tau \cdot \tau \cdot q \cdot \tau \cdot \tau \cdot n \cdot \tau = \int L \cdot R</math>  <math>\int L \cdot \tau \cdot L \cdot m = \int L</math>  <math>\tau \cdot \tau \cdot q \cdot \tau_0 \cdot m</math> ?  <math>\tau \cdot A \cdot A \cdot q^2 \cdot n</math> ??            ? Langevin approach:  <math>R \cdot C</math> (noisy)  <math>R</math> (noiseless)  <math>V_n \cdot V_c</math>            ? Variance of thermal noise voltage across C:  <math>\int df \cdot \tau \cdot 1</math>  <math>c \cdot \tau \cdot \tau \cdot f / f \cdot 2</math>  <math>2 \cdot c \cdot 2 \cdot 2 \cdot RC</math>  <math>0 \cdot c</math> ? The result also follows directly from the EPT: Average stored energy in C: <math>W = 1/2 \cdot C \cdot V^2</math> 2 c            ? Resistor R and capacitor C are in thermal equilibrium and there is only one degree of freedom Mean energy stored in C:  <math>W = kT</math>  <math>= \int 1/2 \cdot CV^2</math>  <math>\int 1/2 \cdot kT</math>  <math>= \int 1/2 \cdot V^2</math> ?  <math>2 \cdot 2 \cdot c \cdot 2 \cdot c</math>  <math>Z(j\omega) \cdot R_1</math>  <math>V_n</math>  <math>R_N</math>  <math>Z(j\omega)</math>  <math>V_n</math>            ? The PSD of noise voltage ????? is given by:            ? The variance of voltage ????? is then given by:            ? The variance of the noise voltage <math>V_n</math> can be obtained without computing the integral by using the Bode Theorem stating where         </p>	<p>           C? C0  <math>1 \cdot \lim_{s \rightarrow 0} s \cdot Z(s) \cdot C? \cdot s??</math>  <math>1 \cdot \lim_{s \rightarrow 0} s \cdot Z(s) \cdot C0 \cdot s??</math>            ? Noise PSD of a 1st-order RC circuit  <math>Z(j\omega)</math>  <math>1 \cdot R \cdot R</math>  <math>\tau_{RC}</math>  <math>Z(j\omega) = 1/R</math> ?  <math>j\omega C</math>  <math>\tau \cdot \tau \cdot j\omega RC</math>  <math>\tau \cdot \tau \cdot \tau RC</math> ?  <math>\tau \cdot j \cdot \tau \cdot \tau RC</math> ?  <math>R \cdot V_n</math>            Nyquist theorem ==<math>\int</math>  <math>S_v(f) = 4kT</math>  <math>\tau \cdot \tau \cdot Z(j \cdot 2 \cdot f) \cdot \tau</math> ?  <math>4kT \cdot \tau \cdot R</math>  <math>n \cdot \tau \cdot \tau RC</math> ?            ? Noise variance of a 1st-order RC circuit from the Nyquist theorem  <math>\int 2 \cdot (f) \cdot df \cdot n</math>  <math>\tau \cdot 4kT</math>  <math>\tau \cdot \tau \cdot \tau \cdot Z \cdot j \cdot 2 \cdot f \cdot \tau \cdot \tau \cdot df</math> ?  <math>0 \cdot 0 \cdot df \cdot \tau \cdot 1 \cdot kT</math>  <math>4kT</math>  <math>\tau \cdot R \cdot \tau \cdot \tau \cdot \tau f</math>  <math>/ fc</math> ?  <math>\tau \cdot 4kT</math>  <math>\tau \cdot R</math> ?  <math>2 \cdot \tau \cdot fc</math>  <math>\tau \cdot 4kT</math>  <math>\tau \cdot R</math> ?  <math>\tau \cdot 2 \cdot 2 \cdot RC \cdot C</math>            ? Noise variance of a 1st-order RC circuit (by Bode theorem) C? =C  <math>1 \cdot \lim_{s \rightarrow 0} s \cdot Z(s) \cdot ?</math>  <math>\lim</math>  <math>s \cdot \tau \cdot R \cdot 1</math>  <math>C? \cdot s??</math>  <math>s?? \cdot \tau \cdot s \cdot \tau \cdot RC \cdot C</math>  <math>C0 = ?</math>  <math>1 \cdot \lim_{s \rightarrow 0} s \cdot Z(s) \cdot ? \lim</math>  <math>s \cdot \tau \cdot R \cdot 0</math>  <math>C0 \cdot s??</math>  <math>s?? \cdot \tau \cdot s \cdot \tau \cdot RC</math>  <math>s?? \cdot \tau \cdot s \cdot \tau \cdot RC</math>            ? From the Bode theorem we then have  <math>V \cdot 2 \cdot \tau \cdot kT \cdot \tau \cdot 1 \cdot \tau \cdot 1 \cdot ?</math>  <math>n \cdot \tau \cdot C \cdot C \cdot \tau \cdot \tau \cdot 0 \cdot ?</math>            ? Let us consider the following simple mechanical system consisting of a proof mass ??, a linear spring with spring constant ?? and a linear damper with damping factor ??            ? The deterministic equation of motion of this system in the absence of an external force is then given by:  <math>d^2x/dt^2 + b \cdot dx/dt + k \cdot x = 0</math>            ? According to the dissipation-fluctuation theorem the damping (loss) is associated with noise we need to introduce a noise force to         </p>
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model these statistical fluctuations according to	? Total input referred noise:	Small signal equivalent model ?VG3	? Concept of equivalent noise resistance: •For a noisy resistor, we have: $S \approx 4kT \cdot R \cdot nR$ •Can express a noise voltage $V_n$ as an equivalent noise resistance $r_{neq}$ :	2 I b V
? Using the Equipartition Theorem (1 ? ?? ? ?? = ?? ) and a derivation	nD nD	Inout	?Req	T P 3
2 ??	? SI ???	S 2 Ink	S $4kT \cdot V_n$	Slide 43 Noise Example •1st-Order Low-pass Filter (1/5)
spring	? Equivalent model of a noisy BJT (Langevin approach)	G	? For our noisy OTA, this means:	? Ideal OA (i.e. infinite DC gain and GBW and infinite input resistance) except for noise which is modeled by a simple input-referred noise voltage source $r_{nOA}$ (the two current noise sources are neglected assuming the OA is MOS) ? Output noise voltage for $r_{in} = 0$ :
similar to the one on slide 23 using the equivalent model shown below shows that the PSD of the noise force $f_{nD}(f)$ is independent of frequency and given by:	C	? 4kT	? S ? S ? S ? S	V ? Z
? In general, to model a noisy mechanical system, the system can be modeled by replacing every noisy damper by a noise-free damper and a noise force generator alongside the damper	IC	? ?	? 4kT	? ?I
? To analyze the noise behavior of the system shown below, the rule from the previous slide can be applied	B noisy B	?Gnk ?G	?G2 ? R	? I ? ? H ?V with Z ? R and H
F <sub>n1</sub> ? ? ? ? F <sub>n2</sub> ? ? ? ?	E	for: k	? Inout In1	? 2 ? s ?c
4kBT 4kBT	C	? G2 ?	In 2	nout 12
? b1 ? b2	?InC	? 1•4 ?	In 3	n1 n 2 nOA nOA 12
? Equivalent model of a noisy resistor (Langevin approach)	E	for: k	In 4	1? s ?
R (noisy)	? Equivalent model of a noisy opamp (Langevin approach)	? 1•4	n1 n 2 n3 n 4	nOA
R (noiseless) R (noiseless) In Vn	noisy	nk nDk mk mk	m1 nineq	1? s ?
S ? 4kT ? R n	? Requires 3 uncorrelated noise sources ? All 3 noise sources are needed to have a model independent of the generator impedance ?	W ? L ? f	? Input referred noise resistance in more detail:	? Resulting output noise voltage PSD: c c
? 4kT n	Current noise sources can be ignored for MOS input stages	k k ? ? KF 4kT n	Thermal noise: R	? with
? G ?	? Noise is a small perturbation compared to $f_{nD}(f)$ ? Analysis can use the small-signal equivalent circuit to which all the noise sources are added (Langevin approach) ? The total output referred noise PSD can be calculated as $S_{n,out}(f)$ ? ? k ? ?	? 4kT	? 2? nD1 ? 2? nD3 ?Gm3	S nout
4kT R	where it has been assumed that all the N sources are uncorrelated ? $f_{nD}(f)$ are the transfer functions from each noise source k to the output ? The noise can then be referred to the input by dividing by the square of the magnitude of the transfer function from input to output $H(f)$ , according to: $S_V(f)$ ?	?Gnk	? 2? nD1 ? ? ? ? nD3 ? Gm3 ?	?f ? ?
(single-sided) (single-sided)	S <sub>n,out</sub>	for: k	nineq-th	Z12
? ?? is Boltzmann's constant (k = 1.38 •10 <sup>-23</sup> J/K) ? ?? is absolute temperature in K	H(f) 2 ? S	? 1•4	G G2	?f ? 2 ? ?S
? Equivalent model of a noisy forward biased diode (Langevin approach)	(f)	G ? ? ?G ? G2	G ?1 ? G ?	? S n 2 ? ?
ID Rd noisy Gd In Vn	where it has been assumed that all the N sources are uncorrelated ? $f_{nD}(f)$ are the transfer functions from each noise source k to the output ? The noise can then be referred to the input by dividing by the square of the magnitude of the transfer function from input to output $H(f)$ , according to: $S_V(f)$ ?	? ?	m1 m1	HnOA
S ? 4kT n	H(f) 2 ? S	? ?	m1 ? nD1 m1 ?	?f ? 2 ? S
? Rd 2	(f)	for: k	? ? G ? R	S ? S
S ? 4kT n	where it has been assumed that all the N sources are uncorrelated ? $f_{nD}(f)$ are the transfer functions from each noise source k to the output ? The noise can then be referred to the input by dividing by the square of the magnitude of the transfer function from input to output $H(f)$ , according to: $S_V(f)$ ?	? 1•4	? 2?	? 4kT
? Gd 2	S <sub>n,out</sub>	nk nDk mk mk	? ? nD3	and S
? 2q ? ID	?f ? ?	W ? L ? f	? Gm3 ? = $\frac{1}{2} I$	? 4kT ? ?
(single-sided) ? Shot noise	nout A ?f ? 2	I k k ? ? KF	? 4kT ? ? ?G	? ?1? fk ?
(single-sided)	?Vneq	? Output noise current:	eq m1 nineq-th	I I V ? ?
? ???? is the small-signal conductance of the diode ? Recall: Large signal current through a pn-diode	V V	4kT n	nD1 ? ?1? ?	n1
? Equivalent model of a noisy MOST (Langevin approach)	Vout	Gm3	G ? nout	n 2 R
ID	V V	? Gm 4	eq m1	nOA
noisy	S 2 nR 1	Inout	1/f noise:	? ? m ? ?
InD	S 2 nR 2	? Gm4 ? ?VG3	? 2? ? G ?2 2?	? Substituting into the output noise voltage yields: ? f ?2
? Thermal noise:	? 4kT R1 ? 4kT R2	? In2	nD1 m1 ? 2? ? ? G ?2	8kT ? R
GnD	? Equivalent input noise voltage PSD (assuming no correlation between the noise sources)	I ? I	W ? L ? ?	2 ? ? f ?
? ?nD	? The opamp noise current sources start to dominate at high source impedances	? = $\frac{1}{2} I$	R ? n ? ? m3 ?	? ? f ?
? Gms	? How to calculate the input referred equivalent noise of an OTA?	? m 4 ? ? I ? I	? p ? n ?1? ? m3 ?	S ? ? ? c ?
? ? nD	Most general configuration Special case: Ideal voltage source drive	? m 4 ? ? I ? I	? 11 ? p ?	? 4kT
? Gm	Vin	?V ? ?V	nineq-f	? ? ?1? k ?
? 1 WI ? 2	S 2 nR 1	? n1 n3 ?	W ? L ? f	Vnout
? ? n ? ?	S 2 nR 2	nout G	? G ?	? f ?2 1?
?nD	? 4kT R1 ? 4kT R2	n1 n 2 G	W ? L	? f ?2 1?
? ? 2	? Equivalent input noise voltage PSD (assuming no correlation between the noise sources)	n3 n 4	? f W	? ? m ? ?
? Flicker noise:	? The opamp noise current sources start to dominate at high source impedances	n1 n 2 n3 n 4	? L ? f ?	? f ? ? f ? ? c ? ? c ? ? The input-referred noise voltage PSD is then given by:
	? How to calculate the input referred equivalent noise of an OTA?	G3 G4	? G ?	? ? f ?2 ?
	Most general configuration Special case: Ideal voltage source drive	m 3	W ? L ? ?	? ? f ?
	Vin	m 3 m3	11 m1 3 3 11 ? m1 3 3 n ? ? Assuming M1-M2 in weak inversion and M3-M4 in strong inversion:	SV ? 8kT
	These two circuits must result in the same	? Transfer function from $r_{nD}$ to $r_{nout}$ :	? nD1 ?	? R ? ? 2 ? ? ? ? ? 4kT
	Inout! noisy	?Vn noiseless	n1 , 2	? ? ?1? k ?
	Slide 39 Example •OTA Noise Analysis (2/5) ?	H(?) ?	Gm1	nin
	Langevin model of the OTA	Inout ?Vn	? Ib , U	? fc ? ?
		?Vn	? nD3	? ? m ? ?
		? ? ? ?	? 2n3 , 3	
		Gm 1	Gm3	
			? ?	

Optimum  $\gamma$  exists for a given equivalent voltage and current noise  
For sufficiently large A:  
 $v_x \approx 0$   
 $v_{out} \approx v_x$   
 $\gamma \approx C_{in} C_{FB}$

? Question: How to choose  $W$  and  $B$  for an optimum SNR?  
 ? Circuit analysis: Compute  $\gamma$  for the 2 circuits and equate them:  
 $C_1 C_2 S \neq FBGS$  in  $S$   
 vneg

C ?G  
ind  
? in m ?Gms  
? WI and saturation  
S ? 4kT ? ? 2  
inD

?? ?G  
SI and saturation  
??3 ms  
G ? n ?G ,  
V ? VG ?VT0  
ms m P n

2 G ? ? ?C  
? ? W  
??V  
?V ? ? ?  
2IIBIAS  
C ? ?C

?W ? L  
m ox ? L ? P S  
n ?V ?V ?  
GS 3 ox  
..\_? ?  
?.? P S

Simulation parameters:  
L ? Lmin  
? 180 nm,  
tox  
? Lmin  
/ 50

? ? 400 cm2 / ?Vs?,  
n ? 1.4  
CFB  
? 100 fF,  
Cin  
? 500 fF

Optimum transistor width:  
 ? Total input referred voltage noise:  
 ?  $C \cdot k \cdot W \cdot C \cdot ?$   
 $S_{\text{neq}}$   
 ?  $4kT \cdot n \cdot ? \cdot F \cdot B \cdot i \cdot n \cdot ? \cdot ?$   
 ?  $j \cdot n \cdot ?$

Simulation parameters:  
L ? Lmin  
? 180 nm,  
tox  
? Lmin  
/ 50

?? 400 cm<sup>2</sup> / ?Vs?,  
n ? 1.4

CFB	? Eopt ? ? ?opt,mag ?opt,mech ?opt,therm	? Eelec ?	? therm ? ? ? ? ? ? therm ? ? ?	? Self-generating sensors require no external
? 100 fF,	?opt,opt ?opt,chem ?opt,elec ? ? Eopt ?	? ? ? ? ? ? ? ? Eelec	therm,os ?	power supply ? Due to the absence of an
Cin	? Eopt,os ?	? ? Eelec,os ?	? Eopt ? ? ?opt,mag ?opt,mech ?opt,therm	external source, there is no additional source
? 500 fF	? E ?	? elec,mag elec,mech elec,therm elec,opt	?opt,opt ?opt,chem ?opt,elec ? ? Eopt ?	of uncertainty/error ? A self-generating sensor
Optimum transistor width:	? ? ? ? ? ? ?	elec,chem elec,elec ?	? Eopt,os ?	draws all its required energy from the
? Total input referred voltage noise:	? ? E	? A simple spring with a proof mass attached	? E ?	measurand (source loading) ? Example:
? C ? k ? W ? C ? 2 1 L 1 Sv ? 4kT ? n ? ? FB in ?	? ? E ?	to a stationary mass can detect accelerations	? ? ? ? ? ? ?	Potentiometer for angle measurements
? ? ? ?	chem ? ?	as displacement mechanical energy (kinetic	? ? E	? Use an additional external source whose
neq	? chem,mag chem,mech chem,therm chem,opt	energy) is transformed into mechanical energy	? ? E ?	energy is modulated to produce the output
C ? ? C W ? V ? V ?	chem,chem chem,elec ? ?	(spring potential energy) ? A mechanical offset	chem ? ?	signal ? The additional source introduces an
? in ? ox P S	chem ? ?	energy can exist because the spring can e.g.	? chem,mag chem,mech chem,therm chem,opt	additional source of error ? A modulating
? Sensor: A device which converts information	chem,os ?	be prestressed	chem,chem chem,elec ? ?	sensor takes less energy from the measurand
? from one energy domain into the electrical	? Eelec ?	? The transduction inside a sensing element	chem ? ?	? Example: Non-contact displacement
domain ? In the electrical domain, (analog)	? ? ? ? ? ? ? ? Eelec	can also take place via multiple transduction	chem,os ?	measurement
signal conditioning, digitization and finally	? ? Eelec,os ?	steps. Such a transducer is called a tandem	? Eelec ?	The code tracks on the rotating disc allow for a
digital signal processing (DSP) and storage	? elec,mag elec,mech elec,therm elec,opt	transducer ? Example: an absorptive coating	? ? ?	unique (digital) encoding of the current shaft
can take place	elec,chem elec,elec ?	on a bimetal strip •In the 1st transduction step,	? ? ? ?	angle
? Most sensors provide analog information at	? The additional additive vector models offsets	optical energy (photons) is converted into	? ? Eelec	Illustrations courtesy TU Delft
their outputs ? Analog-to-digital (A/D)	which are often present in sensors	thermal energy •In the 2nd transduction step,	? ? Eelec,os ?	? The resistance of a slab of conductive
conversion is required to benefit from DSP and	Slide 6 Example: Transduction from Emech to	the thermal energy deflects the bimetallic strip,	? elec,mag elec,mech	material can be expressed as:
convenient data displaying and storage ?	Emech ? Blue entries in the transduction	that is the optical energy is transduced into	elec,therm elec,opt elec,chem	where ?? is the bulk resistivity of the material ?
There will be a lecture on A/D conversion for	matrix represent non-zero coefficients	mechanical energy	elec,elec ?	Under mechanical stress (strain) the change in
senor interfaces towards the end of the course	? E ?	? A tandem transducer can be modeled using	? There is one (desired) sensitivity plus 2	geometry produces an associated resistance
? Transduction: Converting a signal from one	? ?mag,mag	two transduction matrices, representing the	cross-sensitivities and an offset ? This could	change
energy domain into another ? Both sensors	?mag,mech	two successive transduction steps ? Note:	be the transduction matrix of a photodiode	?R ? L0
and actuators are transducers ? Typical	?mag,therm	Tandem transduction requires an intermediate	•Desired sensitivity: ??elec,opt	? ? ? ?
signal/energy domains: •Magnetic (Mag)	?mag,opt	non-electrical energy domain ? Example: •In	•Cross-sensitivities: ??elec,elec (e.g.	?0 ? ?L ?
•Mechanical (Mech) •Thermal (Therm) •Optical	?mag,chem	the transducer on the right, acceleration	electromagnetic interference),	?0 ? L0
(Opt) •Chemical (Chem) and •Electrical (Elec) ?	?mag,elec ? ? E	(mechanical energy) is transduced into	??elec,therm(diode current strongly depends	? ?A ==ζ
Sources of uncertainty (error): •Sensitivity to	? ? E ?	displacement (mechanical energy) •To readout	on temperature through ??? = ???/? ? •Offset	2 0 0 0
unintended electrical and nonelectrical	mag ? ? ?	the displacement signal one typically converts	due to dark current	?R ? ?? R0 ?0
quantities •Noise (thermal, 1/f, •)	? ? ? ?	the displacement into a change in capacitance	? Active sensors: Require an external source of	? ?L L0
•Electromagnetic interference (EMI) •	? ? ?mag ? ?	which can be processed by the readout	excitation Examples: •Resistor-based sensors	? ?A A0
? If we write the different signal domains (i.e.	mag,os	electronics, i.e. there is a mechanical to	(AMRs, GMRs, thermistors, •) ? Passive or	? Assuming that the volume stays constant the
energy forms) as a column vector, the	? Emech ?	electrical energy transduction Since there is no	self-generating sensors: Generate their own	expression can be simplified according to
transduction action of a sensor can be written	? mech,mag	intermediate transduction step going to a	electrical output signal without requiring	Slide 15 Strain gauges with applied force (1/2)
as a matrix with certain sensitivities acting on	mech,mech	non-electrical energy domain, the	external voltages or currents Examples:	? From previous slide:
an input vector (sensor excitation) and	mech,therm mech,opt mech,chem mech,elec ?	accelerometer on this slide is not a tandem	•Thermocouples (thermoelectric voltage	?R ? ?? R0 ?0
producing an output vector (sensor output	? Emech ?	transducer	generation) and photodiodes (photocurrent) ?	? ?L L0
signal).	? Emech,os ?	? Consider a transduction to the electrical	Modulating sensors: Measure the desired	? ?A , A0
? E ?	? E ?	domain represented by the following	quantity by modulating ? Analog vs. Digital	? A
? ?mag,mag ?mag,mech ?mag,therm ?mag,opt	? therm,mag	transduction matrix	sensors: •Analog sensors provide signals	? ?
?mag,chem ?mag,elec ? ? E	?therm,mech	? E ?	which are continuous in time and amplitude	? ?
? ? E ?	?therm,therm	? ?mag,mag ?mag,mech ?mag,therm ?mag,opt	•Digital sensors provide discretized outputs	? L
mag	?therm,opt	?mag,chem ?mag,elec ? ? E	? Deflection mode sensors: •The sensor	A 0
? ? ? ? ? ? ?	?therm,chem	? ? E ?	response to an input is a •deflection•or more	L 0
? ? mag ? ? mag,os	? therm,elec E	mag	general a deviation from its equilibrium	? For metal films the change in resistivity can
? Emech ?	? ? E ?	? ? ? ? ? ? ?	position in the absence of an input. For an	be modeled according to:
? mech,mag mech,mech mech,therm mech,opt	? therm ? ? ? ? ? ? ? therm ? ? ?	? ? mag ? ? mag,os	ideal sensor, this deviation is proportional to	?L ? 0 ==ζ ? ?R ? ? 0
mech,chem mech,elec ?	therm,os ?	? Emech ?	the measurand of interest ? Null mode	? ? R0
? Emech ?	? Eopt ? ? ?opt,mag ?opt,mech ?opt,therm	? mech,mag mech,mech mech,therm mech,opt	sensors: •The sensors or instruments exert an	? ?strain
? Emech,os ?	?opt,opt ?opt,chem ?opt,elec ? ? Eopt ?	mech,chem mech,elec ?	influence on the measured system opposing	? Bringing the 2 results together:
? E ?	? Eopt,os ?	? Emech ?	the effect of the measurand. Ideally, the	k: gauge factor
? therm,mag	? E ?	? Emech,os ?	influence of the measurand and that by the	Slide 16 Strain gauges with applied force (2/2)
?therm,mech	? ? ? ? ? ? ?	? E ?	sensor/instrument are precisely balanced in	? From previous slide:
?therm,therm	? ? E	? therm,mag	magnitude but opposite in sign, resulting in a	k: gauge factor ? For tensile stress we have
?therm,opt	? ? E ?	?therm,mech	null measurement. This nulling is typically	?L ? 0 ==ζ ? ?R ? ? 0
?therm,chem	chem ? ?	?therm,therm	achieved via feedback. ? Null mode	? For compressive stress the opposite is true
? therm,elec E	? chem,mag chem,mech chem,therm chem,opt	?therm,opt	instruments are very linear and can produce	? ? R0
? ? E ?	chem,chem chem,elec ? ?	?therm,chem	very accurate measurements, however, they	? ?strain
? therm ? ? ? ? ? ? ? therm ? ? ?	chem ? ?	? therm,elec E	are not as fast as deflection instruments	? The simple strain gauge structure on this and
therm,os ?	chem,os ?	? ? E ?	(which are open loop systems)	the previous slides is constructed to give a

offset? Key idea: The offset voltages due to doping gradients, temperature gradients and mechanical stress gradients are 180° out of

phase while the generated Hall voltages are in phase  
? : Hooge parameter (1/f noise model) GF: geometry parameter Rsheet : sheet resistance n: doping concentration  
? A typical (asymptotic) noise PSD of a Hall sensor is shown above ? The lower frequency noise is dominated by the sensor's 1/f-noise ? The white noise part of the spectrum is determined by the thermal noise associated with the loss of the Hall element ? Typical corner frequencies are in the range of 1 to 100 kHz  
? Offset and 1/f noise can be greatly reduced by the so-called spinning current or switched Hall technique ? Intuitive explanation: Assume  $\langle \epsilon \rangle = 0$  furthermore  
Slide 56  
CL K ph as e  
? The spinning current method implemented above produces an output voltage with a DC component equal to the offset and a frequency component proportional to the Hall voltage at the clock frequency (Fourier expansion of a square wave!) ? How is this useful? Answer: The amplifier in the circuit above also possesses an offset and 1/f-noise. By •modulating•the information to the clock frequency we can greatly mitigate the effects of both noise and offset  
? A complete •switched Hall system•consists of •The switched Hall plate together with an amplifier •The demodulation switches to translate the signal from the switching frequency back to DC •A final low-pass stage to remove the signal around the 2nd harmonic  
Conventional Hall readout Low-power Hall readout  
? In a conventional implementation of the spinning current technique, the Hall element and the amplifier are biased with separate dedicated bias currents  
? In the low-power configuration, the bias current for the Hall element is reused to bias the amplifier  
Source: Kejik et al., •Integrated Hall Microsystem with current re-use•, Sensor Letters, vol. 5, 1-3, 2007  
? Spinning current technique applied to 4 Hall elements ? Demodulation is achieved by commuting the input differential pair in the switching box ? Amplification is properly defined by feedback resistors feeding the output signal back to a dedicated feedback differential pair  
? Technology: 0.8 •m standard CMOS technology ? Total current consumption of 2.4 mA •80 •20 ? DDA configuration: •Simple demodulation implementation •Small silicon area ? Spinning current technique: •1/f noise suppression ? Features: •Low-power, small

size •High performance (resolution: 500 nT ) Source: Kejik et al., •Integrated Hall Microsystem with current re-use•, Sensor Letters, vol. 5, 1-3, 2007  
? The so-called •Seebeck effect•refers to the conversion of temperature difference into an electromotive force (emf)  
? Any emf ??emf modifies ohm's law according to:  
 $J = -\frac{1}{T} \nabla T$   
? Eemf ?  
where ?? is the electric potential and ?? is the electric conductivity  
? The Seebeck effect produces an emf ??emf according to:  
Emf  
? S(T) ? T  
Source: [http://n.wiki.kip.edu.a.g/wiki/ki/F\\_ile](http://n.wiki.kip.edu.a.g/wiki/ki/F_ile): The rmo elec tric \_Ge ner ator \_Di agr where ??(??) is the Seebeck coefficient am.svg (material property) and ??? is the temperature gradient ? For •standard•materials, the Seebeck coefficient takes on values from ? 100 ?V/K to 1 mV/K  
? Thermocouples make use of the Seebeck effect to measure the temperature difference between two objects  
? For ??? = 0, the emf induced by the Seebeck effect can be directly measured as a voltage difference ? The measured voltage can be calculated by integrating (•summing up•) all emfs due to material differences inside the sensor shown below  
? From the previous slide: ? Clearly, to maximize the emf, one should use materials with very distinct Seebeck coefficients (e.g. chromel and alumel) ? Note: To compute ??sense one does not need to invert the above equation for every measurement ? Instead, we use the following •trick•:  
Define:  
? From previous slide: ? Typically, ??standard is chosen as 0 •C ? The so-called characteristic function of the thermocouple ??(??) is provided by thermocouple manufacturers and metrology standards for different specific thermocouple types ? Note: To extract the temperature ??sense from the above equation, the reference temperature needs to be known typically evaluated by two different methods •Ice bath•method: Immerse the reference junction in a semi-frozen bath of distilled water at atmospheric pressure ? ??ref = 0 •C (not so practical) •Reference junction thermometer (thermocouples are still useful, because their leads can be exposed to extreme environmental conditions)  
? The table lists some commonly used materials for thermocouples:

material stack sensitivity (at 0•C) [-V/K] range [•C] iron/constantan 45 0..760 copper/constantan 35 -100..370 chromel/alumel 40 0..1260 platinum/Pt+Rd 5 0..1500 ? Thermocouples give quite small output voltages, however, they are intrinsically offset free because they always measure a temperature difference which results in ??emf = 0 for ??? = 0 K ? The small output voltage is problematic due to the non-zero offset of real-world voltage amplifiers ? Solution idea: We could increase the emf, by connecting many thermocouples in series •  
? According to the previous slide, one can increase the output voltage of a thermocouple by connecting many of them in series resulting in a so- called thermopile  
? While the problems associated with the small output voltage are solved, a new problem arises: •There is increased thermal conduction between cold and hot parts increased source loading and more heat flux required to build up a temperature difference  
? Transistors are natural temperature sensors ? However, manufacturing tolerances cause temperature errors of up to 3•C  
? Key idea: Producing a temperature stable reference which cancels a positive temperature coefficient with a negative one with  
VREF ? T ?? VCTAT ? T ?? K ? VPTAT ? T ?  
??PTAT ?? a voltage which is proportional to absolute temperature ??CTAT(??) a voltage which is complimentary to absolute temperature  
?? a temperature independent constant which makes ??REF temperature ? This type of reference is known as bandgap reference independent of  
? Collector current of a BJT as a function of its base emitter voltage and emitter area for ??BC = 0 (diode connected device)  
? VEB  
? VEB •kT q  
VEB  
 $I = I_0 \exp\left(\frac{q}{kT} V_{BE}\right)$   
? ?ekT q  
?  $I_0$  ?  $I_0$  ? A  
? ekT q  
C VBC ? 0 S E ? ? S E  
? Conversely, the base emitter voltage can be expressed as a function of the collector current VEB  
? kT q  
?  $\ln\left(\frac{I_C}{I_0}\right) = \frac{q}{kT} V_{BE}$   
?  $\ln\left(\frac{I_C}{I_0}\right) = \frac{q}{kT} V_{BE}$   
? S E ? S E ?  
? A PTAT voltage can be generated using 2 diode connected BJTs  
VPTAT  
? VEB

? VEB1 ? VEB2  
? kT  
?  $\ln\left(\frac{I_C}{I_0}\right) = \frac{q}{kT} V_{BE}$   
?  $\ln\left(\frac{I_C}{I_0}\right) = \frac{q}{kT} V_{BE}$   
q ? I ? A ? q ? I ? A ? ? S E 1 ? ? S E 2 ?  
? kT ?  $\ln\left(\frac{I_C}{I_0}\right) = \frac{q}{kT} V_{BE}$  IS?  
? AE 2 ? ? kT  
?  $\ln\left(\frac{I_C}{I_0}\right) = \frac{q}{kT} V_{BE}$   
q ? I ? A  
?  $I_0$  ? q  
? A ?  
?? S E 1  
q ??  
? E 1 ?  
? Numerical example: ??E2 = 10 ? ??E1  
? 1.381?10<sup>23</sup> J/K 199 ?V  
VEB ?  
1.6 ?10<sup>23</sup> 19 C  
?  $\ln\left(\frac{I_C}{I_0}\right) = \frac{q}{kT} V_{BE}$  ? T ?  
K ?T  
? Note: A true CTAT voltage does not exist! ? Best approximation: Start from the current through a pn diode: VEB  
 $I = I_0 \exp\left(\frac{q}{kT} V_{BE}\right)$   
? ekT q  
?  $I_0$  ? e  
, E : bandga p energy, E  
? 1.13 eV (Si)  
D S S g g  
 $I = I_0 \exp\left(\frac{q}{kT} V_{BE}\right)$   
? T ? ,  
? ? 3, I  
? I ?  
?Eg ? e kT  
Eg •kT =  $\frac{q}{kT} V_{BE}$  •I ,  
 $I = I_0 \exp\left(\frac{q}{kT} V_{BE}\right)$   
S 1 S S s s D  
kT ?  $I_0$  ? ? K  
? T ? ?  
VEB  
? Eg / q ? ?  $\ln\left(\frac{I_C}{I_0}\right) = \frac{q}{kT} V_{BE}$  s ? ?? VG  
? UT ?  $\ln\left(\frac{I_C}{I_0}\right) = \frac{q}{kT} V_{BE}$  1 ?  
m mq  
? ID ? ? ID ?  
V G UT  
VG ? VGO  
? a ?T  
(good from 200 K to 400 K)  
? The terms ????  
and ? ??? ?  
provide the desired CTAT voltage while the temperature dependence in the argument of the natural logarithm is undesired results in curvature of the CTAT voltage and therefore in an error in the •temperature independent curvature correction (not covered  
? Basic structures:  
? Series form: ??  
= ??

? ??  
+ ??  
= ??? ? ??  
+ ??  
REF  
PTAT 2  
CTAT  
??1  
PTAT  
CTAT  
? Parallel form: ?? =  
? ?? = ??? ? ??  
+ ???  
? ??  
REF  
3 ??1  
PTAT  
??2  
CTAT  
? To achieve temperature independence, the resistor ratios and other parameters must be adjusted to result in ???????????? = 0 ??????  
? Simple realization of the series bandgap form: ? Assume ?????????? = 0 and an ideal opamp V ? VEB1 ? VEB2  
? U ?  $\ln\left(\frac{I_C}{I_0}\right) = \frac{q}{kT} V_{BE}$  I 1 ? ? U  
?  $\ln\left(\frac{I_C}{I_0}\right) = \frac{q}{kT} V_{BE}$  I 2 ?  
T ? A ? I ? T ? A ? I ? ? E 1 S ? ? E 2 S ?  
? U ?  $\ln\left(\frac{I_C}{I_0}\right) = \frac{q}{kT} V_{BE}$  I 1 ? AE 2 ? ? U  
?  $\ln\left(\frac{I_C}{I_0}\right) = \frac{q}{kT} V_{BE}$  R 1 ? AE 2 ?  
T ? A ? I ? T ? R ? A ? ? E 1 2 ? ? 3 E 1 ? ? The opamp ensures that the voltage drops across ??3 and ??1 are equal, i.e. ??1 ? ??3 = ??2 ? ??1  
==  $\frac{q}{kT} V_{BE}$  V ? V ? I ? R ? V ? V ? R 1 ? V ? R 1 ? U  
?  $\ln\left(\frac{I_C}{I_0}\right) = \frac{q}{kT} V_{BE}$  R 1 ? AE 2 ? ? V  
? R 1 ? U  
?  $\ln\left(\frac{I_C}{I_0}\right) = \frac{q}{kT} V_{BE}$  R 1 ? AE 2 ?  
REF EB1 1 3 EB1  
R2 R  
EB1 R  
T ? R ? A ?  
CTAT R  
T ? R ? A ?  
2 2 ? 3 E 1 ?  
2 ? 3  
E 1 ?  
? Differentiating w.r.t. to ?? and equating the result to zero yields  
R 1 ?  $\ln\left(\frac{I_C}{I_0}\right) = \frac{q}{kT} V_{BE}$  R 1 ? AE 2 ? ? VGO ? VCTAT ? ?  
?  
? UT  
R ? R ? A ? U 2 ? 3 E 1 ? T  
? For ??OS ? 0, ??REF becomes:  
? R ? R  
? R ? A ? V ? ?  
V ? V  
? ? I ? 1 ? ? V ? 1 ? U  
?  $\ln\left(\frac{I_C}{I_0}\right) = \frac{q}{kT} V_{BE}$  1 E 2 ? I ? OS ? ?  
REF BE1  
R 2 ? R 2  
? R 3  
? AE 1 ? I

2 ? R1 ? ?  
?  
? Recap: A temperature independent voltage can be obtained by adding the PTAT and CTAT voltages ??REF: temperature independent (bandgap) voltage ??EB: CTAT voltage ?? ?  
???EB: PTAT voltage ? New: The ratio of the PTAT and reference voltage ??REF can be used as a measure of temperature  
? Using a current mirror ratio of ??, an emitter area ratio of ?? = ???2/???1 and an amplifier gain of ?? results in  
VPTAT  
? K ? kT q  
? ln? p ? r ?  
? The CTAT voltage is obtained from ??EB2, the ADC computes the ratio of ??PTAT and ??REF to obtain ??  
? Why don't we just measure ??PTAT because it is already proportional to absolute temperature? We could certainly do that. However, we want a digital output and every ADC needs a reference voltage The smartness of the sensor comes from the fact that we use a temperature independent quantity (the bandgap voltage) as reference for the sensor Moreover, when choosing the (digital) ADC offset (??) and gain (??) correctly, the digital codeword is directly a digital temperature reading  
Pertijis et al., JSSC, Dec. •05  
? CMOS process use substrate PNPs ? Spread in ??? use one room temperature trim to obtain an absolute temperature measurement  
? Inaccuracy j •0.1 •C (3??) from ?55 •C to 125 •C (military range)  
? Capacitive sensors are very suitable for displacement measurements  
? Parallel plate capacitance approximation  
C ??  
?? ? A ?? ? A, ? ? 1 for air  
0 r h h r  
1 2 3  
C ??  
? w ?x0  
? ?x ?  
C ??  
? A  
C  
? ?  
? A  
?C ? C ? C0  
h ? ? w h  
? ?x  
C0 ? ?  
h ? ?z ? A h  
top  
Cbot  
? ? ?  
h ? ?z A  
h ? ?z

Linear Nonlinear Reduced nonlinearity due to differential measurement 3  
Charge amplifier  
vout  
? Csense CFB  
? vex  
Voltage amplifier  
vout  
? Av ? C  
Csense ? C  
vex  
sense ref  
Transimpedance amplifier  
vout ? s ? RFBCsense ? vex  
? The node ??sense has no DC connection to gnd (it is a •floating node•) The DC potential is not well defined •The node is very sensitive to leakage currents charging/discharging the node ? A bias resistor provides a well-defined DC bias point The value of ??BIAS needs to be large because ??BIAS together with the capacitors forms a high pass whose corner frequency needs to be sufficiently low compared to the excitation frequency to avoid signal attenuation and discharge during the periods where the excitation voltages stay constant •The large RC-time constant associated w/ large values of ??BIAS causes a slow discharge of the node against drifts ? We can also use a periodic reset using a switch (reset requires introduction of reset phase, where ??p+ = ??p? = 0)  
A. Burstein and W.J. Kaiser, •Mixed analog-digital highly sensitive sensor interface circuit for low-cost microsensors•, Intl. Conf. On solid-State Sensors and Actuators, June 1995 ? The circuit uses correlated double sampling to reduce offset, charge injection and 1/f noise ? During ???1 the excitation voltage is applied to the bridge ??sense changes its value according to the change in capacitance of ??sense1,2 the corresponding voltage is sampled on ??1 Note: ??sense also contains errors due to charge injection, amplifier offset and amplifier 1/f noise ? During ???2 zero volts are applied as excitation voltage to the bridge ??sense now contains only changes due to errors (charge injection etc.) This voltage is stored on ??2 and subtracted from the voltage on ??1  
? When using a voltage amplifier to readout the capacitive difference between ???1 = ?????? + ???/2 and ???2 = ?????? ? ???/2, ??out becomes very sensitive to parasitic capacitances at the center node v ? ?C ? A ? v  
out  
2C ? C ? C  
v in  
s0 p1 p2 ? Parasitic capacitances associates with interconnects can be bootstrapped out by using a voltage buffer driving the shield potential ??shield

v ? ?C  
? A ? v  
out 2C ? C ? C  
v in  
s0 p1 p2  
? Intrinsic sensor parasitics can typically not be bootstrapped out (e.g. the capacitance associated with the anchor area of a released MEMS)  
? In the TIA (transimpedance amplifier) readout circuit the effect of ??p is attenuated by the gain of the opamp ??(??)  
v ? 1 ?  
s ? Csense ? RFB  
x 1 ? A ?s ? ?C ? C ?R  
ierorr  
1 ? s ?  
? s ?Cp ? vx  
sense p FB 1 ? A ?s ?  
? Also in the charge amplifier, the virtual gnd node introduced by the opamp mitigates the effect of ??p  
vx ?  
?C CFB  
? 1 1 ?  
? C  
?  
C p  
?  
A  
? s  
?  
C F B  
ierorr  
? s ?Cp ? vx  
? Assuming an ideal opamp  
?vin,op  
? 0,  
iin,OP  
? 0 ==?z  
iin ?  
j ? ? ?Cin ? vin ?? ?  
iFB  
? ? j ? ? ?CFB ? vout ?? ? ? iin  
? ??in can be the sensing capacitance of a capacitive sensor ? Then, for lateral displacement sensing ??in = ===== + ???, ??? ?? ???  
? For vertical displacement sensing ??? = ===== + ???, ??? ?? ???/(1 + ???)  
? For an ideal opamp:  
? In practice: •The opamp is non ideal (finite DC gain, finite GBW and finite input impedance) •The opamp can have a nonzero DC bias current to avoid opamp saturation a discharge of ??FB is required (continuous or discontinuous)  
? Frequency response of the charge amplifier with finite gain and GBW opamp  
? In a typical charge amplifier, the excitation voltage ??in is attenuated, i.e. ??out j ??in because ??in ? ??FB Features ? Excitation

voltages up to the opamp's GBW are possible  
? The negative opamp input is a virtual gnd and can thus be used for adding currents in a differential sensor structure  
? The differential readout topology shown above is frequently used to read out MEMS structures such as accelerometers and gyroscopes  
? The output signal is proportional to the half-bridge excitation voltage •??ex any error in •??ex will directly translate into an output error Accuracy is particularly important when sensing small values of ??? Mismatch (or drift) of the two amplitudes will introduce errors ? For sinewave excitation the signals •????? can be generated using a center-tapped transformer or an active balun. This configuration is called a Blumlein bridge  
? For rectangular excitation signals and switched excitation schemes, the signals can be generated using the scheme below  
? Assuming ideal opamps (??op ? ?)  
==?z v x2  
? v x1,  
v x3 ? 0  
? The part of the circuit highlighted in red is a simple inverting amplifier with input voltage ??outn and output voltage ??outp ? The part of the circuit highlighted in blue is a simple non-inverting amplifier with input voltage ???1 and with its reference potential pulled to ??outp ? The part of the circuit highlighted in green is a voltage divider between ??in and ??outp  
? From the inverting amplifier subcircuit it directly follows  
? The noninverting amplifier subcircuit enforces the following relations  
voutn  
? vx1  
? vx1 ? ??voutn ? ==?z  
R R vx1 ? 0  
? The resistive divider finally enforces the following relation between ??in and ??outp  
v ? v  
vx1 ? 0 x1 outp  
in x1 ? ==?z R R  
A. Burstein and W.J. Kaiser, •Mixed analog-digital highly sensitive sensor interface circuit for low-cost microsensors•, Intl. Conf. On solid-State Sensors and Actuators, June 1995 ? Idea: Introduce FB to regulate either the positive (shown) or the negative supply to provide a truly balanced excitation ? Working principle: Use a pair of reference capacitors ???1, ???2 (matched to ???1 and ???2) to measure the mismatch between the positive and negative excitation voltage ? The FB loop enforces ??ref = 0 by adjusting the magnitude of the positive excitation voltage  
? Capacitance to displacement relation for  
? Linearization for small displacements

Output is approximately proportional to displacement!  
? For open loop readouts typically a lock-in detection scheme is used to maximize SNR ? For large excitation signals the sensor non-linearity becomes an important issue ? This is true for all open loop sensor readout systems  
Integrated Interface Circuits •Chapter 2: Sensor types  
? Using an inductor, we can embed any capacitive sensor into a resonant circuit w/ resonant frequency ???res (Note: The self resonant frequency of the sensor has to be significantly larger than ???res)  
Q ? Rcoil ? Rloss ? ? 1 ? ? ?  
res 2 LC  
?LC ?  
M. Lemkin and B. Boser, •A three-axis micromachined accelerometer with a CMOS position-sense interface and digital offset-trim electronics, JSSC, pp- 456-468, April 1999  
? Differential readout topologies greatly suppress common mode interferences (power supply noise, charge injection, substrate noise)  
? Using the differential charge integrator on the top right with the drive signal applied to the proof mass, only one excitation source is required ? The output signal of this structure is given by ? ?  
? ?C ?  
C ? ?C  
? ?C C ?  
?V ? ??V  
? ? s ? ?1? s ? ? i p ? s ?  
out ex ? C  
? C ? C ? C ?  
C C ? C ? C ?  
? i ?  
••s  
••i  
••,p ?  
••i  
••,s  
••j  
•,p ?  
? gain error  
offset error ?  
? ?  
M. Lemkin and B. Boser, •A three-axis micromachined accelerometer with a CMOS position-sense interface and digital offset-trim electronics, JSSC, pp- 456-468, April 1999  
? W/o the input common mode feedback (ICMFB), the opamp's input common mode voltage would make steps ???ICM in response to the steps in ??? The opamp needs a large input CMR and CMRR ? The CM feedback amplifier senses the input common mode voltage of the main opamp, compares it against a reference and applies the required voltage at the foot point of the bridge formed





? av Dav Dav ?  
? Now, we need to solve this equation for ???G  
= ??OS, resulting in  
? Finding from previous slide  
? ??mav/??Dav is an important parameter  
which largely varies vs. the operating point of  
a MOSFET ? Moreover, the above derivation  
also holds true for BJTs with the  
difference that ??????  
? 0 for BJTs (????  
= ???? ??  
is equal for both devices)  
? The achievable offset voltages can thus be  
summarized as follows:  
10 mV ? 2 ??ov  
1 ? 100 mV  
MOS (Si)  
1 mV  
120 ?V  
1 ? ? 1/26 mV ?? no change  
BJT  
With offset trimming (Laser, fusible links)  
? In a real-world differential pair mismatch and  
finite output impedance of the current source  
also lead to finite CMRR ? As before,  
decompose all quantities according to  
? G G  
? G , G  
Gm1 ? Gm2  
m m1 m2 mav 2  
? R R  
? R , R  
RL1 ? RL2  
L L1 L2 Lav 2 ? Then, performing a simple  
nodal analysis yields  
? Using the result from the previous slide, the  
CMRR of a diff pair becomes  
CMRR 20 ? log? A  
ADM ? ?  
ADM  
?  
? ?Gmav ? RLav  
CM-to-DM ?  
ACM-to-DM  
? ? ?Gmav ? ?RL 2G  
? RLav ? ?Gm ? ? r  
mav out  
?  
? Relating ???m/??mav to physical parameters,  
we obtain:  
G ? , I  
? ?av  
? ?V ?V  
? nV ?2  
? G ?  
? Gm  
? ??  
? ?Gm ?  
?ID ?V  
mav  
Day 2n  
G T0 S

m ??  
?I ?V T0  
D T0  
? Note:  
Question: Is there any link between CMRR and  
offset?  
? Expression for ??OS assuming random  
fluctuations in ?????, ? ?? and ??????? the  
signs of the individual terms do not matter  
(worst case all are added)  
? Expression for (linear) CMRR assuming  
random fluctuations in ?????, ? ?? and ???????  
(again worst case all are added)  
? These two expressions look quite similar,  
ignoring the little difference  
caused by the factor of 1 2  
and multiplying the two expressions, we find:  
? From previous slide ? Note: ??mav ? ??ov =  
??BIAS  
? Recall: ??out  
= ???? (? ?BIAS/2)  
where ?????  
is the modulation voltage (modeling  
channel length modulation) ? Note: Our  
derivation actually also holds true for BJTs and  
MOSFETs in weak inversion  
? The power supply rejection ratio(s) is/are  
defined as:  
Slide 16 PSRRVDD calculation ? First let us  
calculate the PSRR for the positive supply,  
PSRRVDD ? As long as the finite output  
conductance of ??1 and ??2 are neglected,  
mismatch in ??L1,2 and ??1,2 result in no  
differential output voltage, i.e. infinite  
PSRRVDD ? Assuming:  
RL1 ? RLav  
? ?RL,  
RL2  
? RLav  
? ?RL  
Gm1 ? Gmav  
? ?Gm,  
Gm2  
? Gmav  
? ?Gm  
and finite output conductances of ??1,2 of  
??outM1,2, the resulting PSRR becomes  
resulting in a PSRRVDD of  
Slide 17 P????RRV????????? calculation ?  
Assuming:  
RL1 ? RLav  
? ?RL,  
RL2  
? RLav  
? ?RL  
Gm1 ? Gmav  
? ?Gm,  
Gm2  
? Gmav  
? ?Gm  
and finite output conductances of the current  
source ??out, the resulting PSRR becomes

? Recall from the previous slide:  
Integrated Interface Circuits •Modulation  
techniques to improve low frequency  
performance  
Jens Anders Institute of Smart Sensors  
Department of Electrical Engineering and  
Computer Science University of Stuttgart  
? Synonyms: coherent detection, synchronous  
demodulation, lock-in amplification, chopping  
? These are all modulation techniques that are  
used to improve the low frequency  
performance of measurement systems ? When  
square-wave modulation is employed the  
technique is referred to as chopping ?  
Chopping leads to improved low-frequency  
specifications e.g. reduced offset and 1/????  
noise, better CMRR and PSRR  
? Characterized by •Offset, gain error •Drift,  
1/???? noise •PSRR, CMRR ? Offset, gain error  
and 1/???? noise are caused by component  
mismatch and non-idealities they are a part of  
life ? But we can reduce their effects by •Static  
techniques like calibration and trimming  
•Dynamic techniques such as chopping,  
auto-zeroing and dynamic element matching  
? Involves measuring a static error of a system  
(e.g. offset or gain error) and then adjusting  
the value of a component in order to reduce  
the error to zero + Low complexity + No  
bandwidth limitation - Requires measurement  
equipment ? Also requires a memory element  
to store the trimmed value e.g. a  
potentiometer or a PROM C  
Vin  
Vout  
? Techniques which continuously attempt to  
cancel the effect of system non-idealities to  
zero. + (Usually) do not require measurement  
equipment + Also compensate for drift and  
1/???? noise and improve CMRR and PSRR -  
Requires more complex circuitry - Reduce  
bandwidth  
? Two main Dynamic Offset Cancellation (DOC)  
techniques are: Chopping and Auto-zeroing  
? Time domain: Auto-zeroing periodically  
measure the offset (the noise) and subtract it  
from the input signal ? Frequency domain:  
Chopping modulating the input signal above  
the 1/???? noise  
? Signal is modulated, amplified and then  
demodulated ? DC offset is modulated once  
and the resulting AC signal can be removed by  
a low-pass filter ? The modulators are usually  
implemented as polarity reversing switches,  
known as choppers ? The technique is known  
as chopping  
? Easily generated modulating signal ?  
Modulator is a simple polarity-reversing switch  
? Switches are easily realized in CMOS  
? Output chopper converts offset into a  
square-wave ? To avoid residual offset, the

duty-cycle of the square-wave should be  
exactly 50? Non-ideal LPF residual ripple  
? Complete suppression of 1/???? noise if  
?????ch ? 1/???? corner frequency  
but harmonics slightly (?? 8  
? 1.23) higher noise power  
because noise from higher harmonics folds  
into baseband ? Up-modulated offset must be  
filtered out loss of signal bandwidth and  
residual chopper •ripple•  
xsquare ?t ? ?  
4 ? ? k ?1  
sin?? ?2k 2k  
? 1?? fch ? 1  
? t ?  
? Turning off/on the switch injects charge in  
??L ? How much of the charge is added to ??L?  
•Usual assumption: The charge splits half-half  
•In reality the amount of charge is a complex  
function of the impedance at each terminal  
and the transition time of the clock ? ???? is  
linear (proportional) w.r.t the transistor area  
???? ? ?? and nonlinear w.r.t. ??in  
Q ? W  
? L ?C ? ?V  
?Vin  
?VT0 ? ??  
? ? ? ?out can be decomposed into a term  
linear w.r.t ??in and a 2nd term nonlinear w.r.t  
??in Distortion ? ?  
V ? V  
?1? W  
? L ?Cox  
? ? W  
? L ?Cox  
? ?V ?V  
? ??  
out  
in ?  
2C ? 2C  
? ? T0 ?  
•L•, ? gain error ?  
•L •••••, offset , distortion  
? Capacitive coupling due to ??OV capacitive  
divider between ??OV and ??L  
? Clock transition couples to ??out and creates  
an error  
? ???out is independent of ???in  
? ???out is linear w.r.t capacitive divider ratio  
constant offset  
? Clock asymmetry (non-50? Spikes at the  
amplifier's output due to clock feedthrough  
and charge injection ? Demodulation of these  
spikes back to DC by the output chopper  
residual offset (in the range of millivolts) ?  
Residual offset is proportional to the chopping  
frequency  
? Limited amplifier bandwidth results in an  
output signal which is not a perfect  
square-wave less power at the harmonic less  
gain ? Chopping reduces DC gain

? Chopping is a powerful technique that can be  
used to reduce offset and 1/???? noise in  
amplifiers and systems  
? Main drawback: the need for a LPF to remove  
the up-modulated offset bandwidth limitation  
? Main non-idealities are caused by:  
bandwidth, clock asymmetry and chopper  
spikes  
? Offsets as low as a few nV can be achieved  
? Three-stage amplifier, first two stages are  
chopped ? 1 mHz 1/???? corner frequency, 5 •V  
offset voltage, CMRR , PSRR ? 120 dB  
R. Wu, K.A.A. Makinwa and J.H. Huijsing, "A  
Chopper Current-Feedback Instrumentation  
Amplifier With a 1 mHz Noise Corner and an  
AC-Coupled Ripple Reduction Loop,"  
Solid-State Circuits, IEEE Journal of , vol. 44,  
no. 12, pp. 3232-3243, Dec. 2009  
Analog Storage Digital Storage  
Vin  
Vo ut  
Vin  
?? S ?1  
A 1  
N Vn CLK  
V o u t A2  
SAR = Successive Approximation Register  
DAC ? Sampling the unwanted signal (noise  
and offset) during ?1 ? Storing this value  
(analog or digital) ? Subtracting the stored  
value from the input signal during ?2 ?  
Amplifier is disconnected from signal path  
during ?1 ? An auxiliary port N can be used to  
apply the stored value offset and  
low-frequency noise can be greatly reduced  
Vref  
? S1 and S2 are closed ??out = ??OS ? The  
amplifier's offset is stored on ??az  
? S3 is closed output signal is available ? For  
an amplifier with finite DC gain ??, the residual  
offset is given by ??OS/(?? + 1)  
? Clock feedthrough and charge injection  
errors in stored offset  
? Stored offset on ??az will slowly leak away  
? In practice, ??az is made as large as possible  
? Use minimum size switches (subject to noise  
, speed requirements)  
? Use differential topologies for 1st order  
cancellation  
? Use complementary switches  
? Use dummy switches  
? Use bottom plate sampling  
? The error in the differential output signal can  
be written as:  
?Q2  
? ?Q1 ? W ? L ?Cox ???Vinp  
?Vinn ? ? ?VT02 ?VT01 ???  
? W ? L ?Cox ??Vinp  
?Vinn ? ? ? ? 2?F  
? VT02 ?  
2?F  
? VT01 ??

? ? perfect cancelation is only achieved for zero differential input signal (??inp = ??inn) ? BUT: The constant offset as well as the nonlinearity due to the square root term are reduced compared to a single-ended switch ? Use an NMOS and a PMOS switch in parallel we can achieve a first order cancelation of the opposite charge packets. To this end we need: Consequently, the drain source cancelation can only occur for one input level ??in ? Also for clock feedthrough, there is not a perfect cancelation due to the different overlap capacitances of NMOS and PMOS ? Assuming the charge injection due to ??1 is: ? Then, since the charge injection of ???2is for ???2 = ??1 and ?????2 = 0.5 ? ???21 the two charge packages cancel ? Unfortunately, the assumption of equal charge splitting of ??1 is in general not valid ? Fortunately, the above choice of ???2 also mitigates clock feedthrough ? Switch ???2 opens slightly earlier than ??1 the charge injected by the opening of ???2 is constant and can be eliminated by using differential sampling ? Since the bottom plate of ??az is floating when ??1 is opened, no charge is injected on ??az ? This scheme works very well but requires an additional clock signal Slide 29 Effect of Autozeroing on Noise VC R VN When switch S is open: VAZ VAZ ? VN ?VC for: RC •TAZ ? Each time the switch ?? is closed, the output voltage ??AZ is reset to zero and the noise source voltage ??N appears across resistor ?? and capacitor ?? ? Assuming ??? ? ??AZ at the end of the sampling phase (when switch ?? opens) the noise voltage is sampled onto capacitor ?? ? The output voltage ??AZ becomes equal to the difference between the instantaneous voltage ???? and the voltage ???? stored on ?? DC component of ???? is eliminated but HF is passed ? If the source voltage ????(?) corresponds to a stationary random noise with PSD ??????(????), the PSD of the autozero voltage ???????(?) across the switch can be decomposed into two components: •One caused by the baseband noise (which is reduced by the autozeroing process) •And the other one created by the foldover components introduced by aliasing: S ?f ? ? H ?f ? 2 ? S ?f ? ? Sfold

0••-•VN•, baseband •fo.Id •, foldover where: Sfold ?f ? ? ?? n??? n?0 2 Hn ?f ? ? S ? ? n ? ? ? Ts ? ? The baseband transfer function is given by: 2 ? ? sin?2? ? f ?T ??2 ? cos?2? ? f ?T ??2 ? H ?f ? ? d 2 ? ? ?1? h ? ? ?1? h ? ? ? ? ? f ?T for ? ? f ?T •1 0 ? 2? ? f ?Th ? ? 2? ? f ?Th ? ? where ?? = ???/???? is the duty cycle (???? = ??? + ????????) S ?f ? ? H ?f ? 2 ? S ?f ? ? S ?f ? VAZ 0••-•VN•, baseband •fo.Id •, foldover Sfold ?f ? ? ?? n??? n?0 2 Hn ?f ? ? S ? ? n ? ? ? Ts ? ? The baseband transfer function imposes a zero at ???? = 0, which cancels out any DC component present in ????(?) ? The transfer functions for ?? ? 0 are given by: ? sin? ? f ?T ??2 H ?f ? ? ?d ? h ? for n ? 0 and T •T n ? ? ? f ?Th ? AZ h S f ? AZ H ?f ? 2 ? S ?f ? ? Sfold ?f ? with: SV ? ?f ? ? S0 1? ?f fc ? ? In order to use the previous analysis, we simply have to replace the voltage source ???? by the noise at the output of the AZ amplifier ? The baseband signal is autozeroed by ?0 2 while the PSD of the autozeroed signal is dominated by the foldover component S ?f ? ? sinc2 ?? ? f ?T ? ? S ?f ?

n ? ? sinc2 ?? ? f ?T ? ? ? ? f ?T ? 1? ? S fold s ? n ? ? ? n ? 0 VN? ? ? ? Ts ? c s c 0 Reference: C. Enz and G.C. Temes, Proc. IEEE, Nov. 1996 S f ? AZ H ?f ? 2 ? S ?f ? ? Sfold ?f ? ? with: SV ? ?f ? ? ? 1 1? ?f fc ? ? The baseband 1/f is eliminated by the high-pass filtering action of ?0 2 ? An additional foldover component is present in the autozeroed output S ?f ? ? sinc2 ?? ? f ?T ? ? S ?f ? n ? ? sinc2 ?? ? f ?T ? ? ?T ? 2 f T ? ? 2 ? f ?T ? ? ? S fold s ? VN? ? T ? c s ? ? k ? s ? ?1? ln? 3 c s ? ? 0 n??? ? s ? n?0 ? ? ? Reference: C.C. Enz and G.C. Temes, Proc. IEEE, Nov. 1996 ? Auto-Zeroing is a powerful offset and 1/f noise reduction technique for amplifiers and systems ? Unlike chopping, it does not suffer from ripples, but its noise performance is worse due to aliasing ? Main non-idealities are caused by switching spikes, leakage currents and (sometimes) by finite gain ? Offsets of a few microvolts can be reached ? CDS is a special case of AZ frequently used in SC circuits ? SC circuits are sampled data systems clock available •Phase 1: calibration phase: ??1 = ??(??1) = ?? ? •Phase 2: operation phase: ??2 = ??(??2) = ?? ? (??2 ? ??1) = ?? ? ??in ? To maximize suppression of 1/f noise, the interval ??1 ? ??2 should be as short as possible

? For small signals, offset dominates (can use AZ, CHS, •) ? For large signals, gain error dominates ? Both gain error and offset are static errors, which can be removed by calibration and/or trimming ? It can also be removed by dynamic element matching (DEM) ? If ?? ? ?? ? 1 ??CL ? 1/?? ? For moderate 1/??, DC-gain of op-amp is large enough ? ??: Resistor/Capacitor ratio •Resistors: 0.01•Capacitors: 1 ? So feedback allows us to replace the inaccurate gain of open loop amplifiers by well defined ratios of passive components Can we do better? ? Idea: In a sensor system we would like to know ??in but we do not know (precisely) ?? and ??OS for 3 unknowns, we need 3 equations ? 3 Phases are required for a measurement: •Phase 1: ??1 = ?? ? •Phase 2: ??2 = ?? ? •Phase 1: ??3 = ?? ? ??OS ??, ??OS and ??in can be found Accuracy is limited by ADC resolution and noise ? Gain errors can be further reduced by using Dynamic Element Matching (DEM) ? DEM involves swapping the position of nominally identical elements within a circuit ? The average error is significantly reduced ? Gain of 2 ? 2 identical resistors i.e. ??1 = ??2 ? DEM can be applied by using switches to swap the position of mismatched resistors in the circuit ? Accuracy is limited by mismatch of switch resistance ? Accurate gain 2 amplifier with DEM ? Average value of ??out ? ??in ? ??out contains AC components which must be removed by a LPF (like in chopping) ? Chopping and DEM can be easily combined ? Mismatch is shifted to the harmonics of ?????DEM ? To avoid unwanted intermodulation, keep ?????in ; ?????DEM/2 ? Pro •Gain (ratio) error can be reduced to ppm levels ? Cons •Switches are required to swap components extra circuit complexity, switching transients •Result must be averaged BW reduction •Input signal must be band-limited (????in ; ?????DEM/2) to prevent inter-modulation products ? Precise gain can be achieved by feedback •discrete resistors: 0.01•on-chip: 0.1? Better performance can be achieved by using DEM, but like chopping, this is at the expense of BW ? If the signal is digitized, the 3-signal method is also effective, but accuracy is limited by ADC resolution Chapter 5 Coherent Detection Jens Anders Institute of Smart Sensors Department of Electrical Engineering and Computer Science University of Stuttgart

? Review: •Synonyms: coherent detection, synchronous demodulation, lock-in amplification, chopping •These are all modulation techniques that are used to improve the low frequency performance of measurement systems •When square-wave modulation is employed, the technique is referred to as chopping ? Today we talk about coherent detection/lock-in amplification ? This technique is very similar to chopping except that one uses a sine wave instead of a rectangular waveform for modulation ? When to use it? •When measuring low-bandwidth or quasi-static signals in the presence of high noise or disturbance levels •If a high dynamic range is required ? Therefore it is often used to readout sensors such as: •(MEMS) Accelerometers (fF of capacitance change) •Optical (infrared) detectors (detecting fA•s of current change) •Magnetic sensors (detecting mV•s of voltage change) •Strain gauges (detecting mV•s of voltage change) ? A coherent detector behaves like a band-pass filter ? Setup: ? ??oM = ??Amp ? ??mult ? ????? ? sin ? ????? sin ? ??oM = ??Amp ? ??mult ? ????????????? ? 2 cos ? cos ? For ???? = ????? (????? is derived from ???? ? coherent signals): ??oM = ??Amp ? ??mult ? ????????????? ? 2 1 ? cos ? ??oM = ??Amp ? ??mult ? ????????????? ? 2 1 ? cos (???? = ?? ???? ? LPF to remove the sum frequency: ??oF = ??LPF ? ??Amp ? ??mult ? ????? ? 2 ? A coherent detector directly extracts the amplitude of the input signal ????? if ??i and ??ref are in phase (Synchronous detection) ? What if they are not in-phase? ? ??oM = ??Amp ? ??mult ? ????? ? sin ????? ? ? + ? ? ????? sin ????? = ??Amp

??mult ??????? 2 cos ? cos [???? +????? ][? + ? ? ?oF = ??LPF ? ??Amp ? ??mult ? ?????????? 2 =0 LPF ? cos ? Phase sensitive coherent detector ? What would be the SNR of ? an oscilloscope (wideband, LPF) ? a coherent detector (narrowband, BPF) ? Some numbers: ? What would be the detection limit of the coherent detector if the white noise spectral density is 10nV/?Hz and fLPF = 1Hz? ??????? ????V ? = ???????? ui ? u-i ? cos ??r t ? ? ? ? Use a quadrature LO to obtain both the phase and the amplitude information ? Linear operation of an analog multiplier circuit, working over a large range of input signals is difficult to realize. ? A much simpler realization is a switching detector aka a chopper ? Chopper realization in CMOS: •Easy: just 4 Transistors •Accurate: no offset introduced •But: switching spikes can cause problems (residual offset) ? An ideal coherent detector is only sensitive to frequency components in a narrow band around a reference signal ??ref ? The LPF determines the signal bandwidth A practical example •ESR DETECTION Analyzing the structure and dynamics of •biomolecules•Source: SREP (http://sites.univ-provence.fr/srep/index.html) Food industry: Quality control Biomedical Imaging •Sensor Fusion Source: S. Liu et al., Applications of in vivo EPR in brain research: Monitoring tissue oxygenation, blood flow, and oxidative stress In-vivo ESR Dosimetry Source: EPR Center Dartmouth College ? What is •spin•? ? A property of some particles like mass and charge ? What do we need to know to detect them? ? A spin ??? always comes along with an angular momentum ??? and a magnetic dipole moment	??? I-?: reduced Planck constant ????: gyromagnetic ratio Parameters: Free electron ???? ?????? ? ????????? 0.24 GHz/T ?????? = ????????? ??????? ????? = ????????? ????T ? ??RF = ??? for ????? = ????. ??? T Circulator operation: Non-reciprocal 3-port w/ S-parameter matrix: ? 0 0 1 ? S ? ? 1 0 0 ? ? 0 1 0 ? Incident power at one port is transferred to the next port ? Sample absorption is a (resonant) function of the static ?????-field ? Resonator containing the sample is critically coupled at Larmor frequency (critically coupled resonator ? no reflected power) ? Static ?????-field is swept through the resonance field Resonant sample absorption changes cavity Q factor Reflected power at circulator output varies as function of ????? CW -ESR spectrum is the reflected power vs. ????? ESR •DC-spectrum Parameters: Free electron ???? ?????? ? ????????? 0.24 GHz/T ?????? = ????????? ????????? ????? = ????????? ????T ? ??RF = ??? for ????? = ????. ??? T ? ESR signal inherits the absorption shape (associated w/ sample loss) ? Resonance condition: ??RF = ??L = ?????????? ? When sweeping ?? ???? , the peak occurs at ?? ???? = ??RF ??? ESR signal generation in the presence of field modulation Resulting ESR signal for small modulation fields ? The •DC•ESR spectrum is relatively noisy due to low frequency disturbances (e.g. 1/f noise and drift) ? The signal is modulated to an IF by modulating the ?????-field ? In this way, a lock-in amplifier can be used to extract the signal Chapter 6 Integrated Interface Circuits •DACs Jens Anders Institute of Smart Sensors Department of Electrical Engineering and Computer Science University of Stuttgart ? Recap: digitization •Time discretization (sampling) •Value discretization (quantization) ? Digital-to-analog conversion ? Analog-to-digital conversion Integrated Interface Circuits •Chapter 6: DACs ? Sampling is the conversion of a time-continuous signal into a value equivalent, time-discrete signal ? Prerequisite: Nyquist sampling theorem: To be able to perfectly reconstruct a band limited signal ???max = ????? from an equidistantly sampled version (sampling frequency ????? = 1/????) of it, the	sampling frequency must satisfy ????? ? ????? = 2 ? ????? ? Quantization: •Value discretization in steps of one LSB •Infinite set of values ? finite set of values •E.g., rounding ? Sample: S is closed, ??out = ??in ? Hold: S is open, C holds ??out ? IC1 with small Zout for fast charging of C ? IC2 with high Zin for slow discharge of C ? Switch: Transmission gate or single FET with small Ron ? Aperture time: time required for the switch to open ? Droop: discharge of capacitor ? Acquisition time: time to switch and charge the capacitor ? Switching transients: voltage buffer ringing ? How to design C ? •Large enough for small droop, small enough for fast charging •Fast charging depends on ??on of the switch and ??out or ??out,max of IC1 •Sufficiently large for sufficiently small kT noise C ? Analog multiplexer use transmission gates which are bi-directional: MUX , DEMUX ? Functionality ? Static DAC errors •Gain , offset error •Differential non-linearity (DNL) •Integral non-linearity (INL) ? Dynamic DAC errors •Jitter, Glitches ? Types of DACs ? Convert transient digital input signal to a transient analog output signal ? Output voltage variation upon the variation of 1 LSB at the input ??LSB ? Maximum (full scale) input voltage ??FS VLSB ? Vref 2N VFS ? Vref 2N ? 1 2N ? Gain error: Offset error: ? Gain and offset errors do not affect linearity! ? If needed, they are easy to compensate •e.g., by pre-processing: scaling, shifting ? Differential nonlinearity (DNL) is a measure of (non-) uniformity ? The vector DNL(k) quantifies for each code k the deviation of the step size from the ideal (or average, in case of gain error) step size of 1 LSB k DNL(k) 000 N/D 001 -0.4 010 0.2 011 0.9 100 -0.7 101 0.9 110 -0.2 111 -0.7 Note: no gain and offset error in this example! ? What if DNL(?) is smaller than ?1? •The output value ?? is smaller than the previous sample ??(?? ? 1) •Characteristic is non-monotonic! ? Critical for feedback structures since non-monotonicity turns negative into positive feedback ? Occurs most often when switching the MSB ? Integral nonlinearity INL(k) is the deviation from the output value V(k) from the ideal output value Videal(k) ? If ????NL ? ???? then	DNL ? ???? (mo noto nicit y) Note: no gain and offset error in this example! ? Clock frequency/phase varies slightly •Clock edges affected by jitter •Uncertainty of the position of the clock edge ? Rough estimation: •Sinusoidal signal: •Maximum change rate: •Maximum jitter for error below one LSB: ? 10-bit DAC with 10 MSamples/s requires 30 ps accurate clock edges! ? Glitches occur when turn-off and turn-on times are not precisely synchronized ? S2 represents the MSB output signal ? S1 represents the (?? ? 1) ? LSB output signal ? Example: transition S1 = 0111 to S2 = 1000 ? Resistor string DAC ? Binary weighted resistive voltage divider DAC ? Binary weighted current source DAC ? Thermometer weighted DAC ? R-2R ladder DAC ? Pulse width modulation ? Simple voltage divider ? Inherently monotonic ? Amount of resistors proportional to 2N •3 bit ? 8 resistors •8 bit ? 256 resistors •Resistors are large Slide 19 Binary Weighted Resistive Voltage Divider DAC (1/2) ? Inverting summing amplifier configuration ? Each bit ???? produces an output voltage according to ? Combined output: ? Impractical for large N: •Area ?? ?? W?? ? ???? ? ????+1 •Resistors need to be very precise, RMSB must have the highest precision ? Current mirror realization of the current sources: ? Few number of resistors / current sources and switches ? Large ratios of resistors, currents and switches (2N) •Monotonicity not guaranteed •5bit: 1uA, 2uA 4uA, 8uA, 16uA •15uA ? 16uA means switch 4 sources off and 1 source on •Assume statistical variations of 10•1u+2u+4u+8u ; 16u is not guaranteed •Linearity •Accuracy •Matching ? Prone to glitches •Large portions of the output are switched on/off ? Current steering DAC: ? Reduced glitches ? Inherently monotonic ? 2N current sources ? Binary to thermometer decoder needed: ? Reduced area: ?? ?? W?? ? ???? (3 ? ?? + 2) ? The current ?? in every branch is given by: ? Looking from node ?????? to the left or right one sees a resistance of 2?? The current flowing through each resistor splits half half ? The current in the branch corresponding to bit ???? times split half half is ???? + 1 ? R-2R ladder DAC: switches change from GND to -Vref ? Solution: inverse R-2R network	•Switches change from GND to virtual GND ? Working principle: •??left •??MSB = 2?? ? ??left = ? ? ?re?? = ? ?????????? 2??? ????????????? •??MSB?1 = ? 2?? LSB MSB ????????????? •?? = ? 2?? 2??1 I M S B AN-1 AN- 2 A0 Z l e f t ? From previous slide: Vout,i ? ddi ? Vref ??R ? ? R 2i ? Vref ? di ? 1 2 i ? 1 LSB MSB AN-1 AN-2 IMSB A0 Zleft ? Summing amplifier with weighted inputs: out C in1 C in2 f f ? Transfer function from bit ???? to the output voltage: cf. slide 19! ? Combined output voltage: ? For N bit ? (2N - 1) + 2N unit capacitors ??unit = ??0/2?? •4 bit ? 15 + 16 = 31 unit capacitors ??0/16 ? Impractical for large N: •Area ?? ?? 2 ? A??unit ? 2?? with ?????unit being the area of a unit capacitor •Capacitors need to be very precise, CMSB must have the highest precision MSB-Group ? Example: 8 bit ? 15 + 1 + 15 + 16 = 47 unit capacitors ? Phase 1: reset Right hand side for 10000000: Right hand side in general: ? MSB group all caps shorted between gnd and virtual gnd do not matter (i.e. do not store any charge) ? From node ??2 to the output the circuit is a simple SC voltage amplifier with a gain of ??out ??A2 ????0 = ? 16 ??0 = ? 1 16 ? Question? What is the voltage at node ???? Slide 34 Realization with less Capacitors •LSB Group (2/4) V ? ? Vref V V 2 ? Vref 1 2 A 2 out ? ? ? 4 Slide 35 Realization with less Capacitors •LSB Group (3/4)
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$V_{DD}$   
 $V_{DD}$   
 $A_2 C_4$   
 $4 \text{ ref } 4 \text{ ref}$   
 $0$   
 $V_{DD} 2 V_{ref}$   
out  
 $2^4$   
Left hand side in general:  
Pulse width modulated bitstream Pulse  
width corresponds to the desired analog  
output voltage RC low pass filter averages  
the PWM signal  
Combination of various architectures  
optimize speed, linearity, glitches, matching  
Commonly used for high performance DACs  
Course DAC (MSBs) feeds fine DAC (LSBs)  
Each source supposed to have  $I_{ref}$  Assume  
particular source has only 90% Calibration  
Phase  $V_{GS1}$  settles so that  $Q_1$  draws 10%  
Operation Phase  $Q_1$  still calibrates so that  $I_{D1}$   
=  $I_{ref}$